

Stamp: OIPE JC98
DEC 29 2004
INTELLIGENCE OFFICE

Group Art Unit: 2823
Examiner: Joannie A. Garcia

Applicant: Masakatsu SAIJO et al.

Appl. No.: 10/648,343

Filed: August 27, 2003

For: METHOD OF MEASURING CONTACT
RESISTANCE OF PROBE AND METHOD OF
TESTING SEMICONDUCTOR DEVICE

) **RESPONSE TO**
) **ELECTION OF**
) **SPECIES**
) **REQUIREMENT**
) **and**
) **AMENDMENT**

Atty. Dkt.: OKI 373

December 29, 2004

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

ELECTION OF SPECIES

Responsive to the Election Requirement dated December 1, 2004, applicants elect Species II, for examination. Claims 5 - 13 read on the elected specie. The election is without traverse.

Applicants maintain the right to filing a divisional application with regard to the non-elected specie. Examination of the application on the merits respectfully is requested.

By making this election and selecting these claims for examination, however, applicants do not restrict the scope of the listed claims to only the features of a particular exemplary embodiment, which claims should be afforded the broadest scope allowed by the relevant prior art.

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